

<b>Notice of References Cited</b>	Application/Control No. 10/615,278	Applicant(s)/Patent Under Reexamination DEAVER ET AL.	
	Examiner April Y. Shan	Art Unit 2135	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0236956	11-2004	Shen et al.	713/193
*	B	US-7,095,853	08-2006	Morishita, Takuya	380/201
*	C	US-5,787,179	07-1998	Ogawa et al.	380/46
*	D	US-2002/0146118	10-2002	DiSanto et al.	380/37
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	wo/2002/100037	12-2002	JAPAN	Shen et al.	713/193
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	World Intellectual Property Organization, 10/23/2006, www.wipo.int, support evidence of WO/2002/100037 publication date
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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